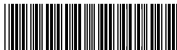


Search Notes**Application/Control No.**

10/537,194

Examiner

John P. Sheehan

**Applicant(s)/Patent under
Reexamination**

TAKASHIMA ET AL.

Art Unit

1793

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR